D metrisis Film Metrology & More

XY-M100: Two-Axis Linear Translation Stage for FR-pOrtable

ThetaMetrisis XY linear stage is a dedicated accessory for FR-pOrtable tool that allows the manual thickness and optical properties mapping of samples fast, easily and accurately.

The linear stage which provides a 100mm of travel along X and Y is suitable for Reflectance and Transmittance measurements since it incorporates an optical window of up to 4-inch wafers.

Features

- Manually controlled (knob on the top)
- o Travel range XY: 100 mm; 100 mm
- Sample stage: max. Diameter 100 mm
- o Spring Clips
- Reflectance & Transmittance
- o Stage size: 285x205x330 mm

Thickness mapping (30mmX30mm) of SU-8 film spin coated on Si wafer with measurement step of 5mm. The thickness (scale bar in um) varies from 14.09 um to 14.40 um.



